

Sample Results Summary Sheet

Please return this form to the Curator for each allocated Sample

Sample ID: RA-QD02-0017

PI: N. Kita and D. Nakashima

Type and date of analysis performed:

Examination of surface profile before ion microprobe analyses, Jul 11, Aug 23, 2012

Ion microprobe analyses of oxygen isotopes, Sep 3 - Sep 7, 2012

SEM observation to inspect Ion microprobe pits, Sep 13, 2012

Examination of surface profile after ion microprobe analyses, Sep 11, Sep 17, 2012

Elements or phases identified: (Mg, Si, olivine, pyroxene, aromatic carbon, etc.)

Oxygen isotopes

Contaminant phases identified: (Al, SUS, carbon particles, etc.)

None

Sample handling: (e.g. exposed in atmosphere, embedded in resin, polished, sliced by FIB or UMT)

Exposed in atmosphere, Embedded epoxy disks in Indium by pressing surface with flat silica glasses, Coated with gold ~ 30nm, Removed epoxy disks from Indium, Polished using 0.25- μ m diamond suspension, Washed with distilled water and ethanol, Coated with carbon ~ 20nm

State of sample pre-analysis: (e.g. N₂ hold, atmosphere, resin embedded, polished section, UTS) (please describe treatments and/or modifications for the sample you have done before your analysis)

Exposed in atmosphere, Embedded in Indium, Coated with gold ~ 30nm,
Kept in a vacuum desiccator

State of sample post-analysis:

(N₂ hold in sample holder, atmosphere, resin embedded, polished section, UTS)

(partially damaged by electron beam, spotted by Ga beam, neutron activation)

(consumed by laser ablation)

(unexpected breakup, into # pieces)

(Lost : reason)

Partly consumed by Cs (2 SIMS pits; 1 SIMS pit ~ 1 ng), C-coated,

Kept in a vacuum desiccator

Analysis data Notes: (summary of the attached analysis data and/or images)

See attached sheets